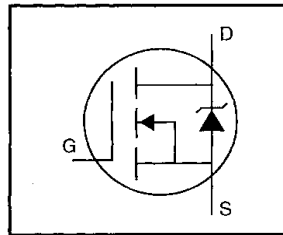


IRL510PbF

HEXFET® Power MOSFET

- Dynamic dv/dt Rating
- Repetitive Avalanche Rated
- Logic-Level Gate Drive
- $R_{DS(on)}$ Specified at $V_{GS}=4V$ & $5V$
- 175°C Operating Temperature
- Fast Switching
- Ease of Paralleling
- Lead-Free

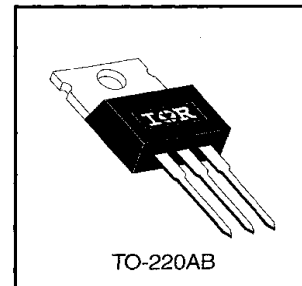


$V_{DSS} = 100V$
$R_{DS(on)} = 0.54\Omega$
$I_D = 5.6A$

Description

Third Generation HEXFETs from International Rectifier provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.



Absolute Maximum Ratings

	Parameter	Max.	Units
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 5.0 V$	5.6	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 5.0 V$	4.0	
I_{DM}	Pulsed Drain Current ①	18	
$P_D @ T_C = 25^\circ C$	Power Dissipation	43	W
	Linear Derating Factor	0.29	W/°C
V_{GS}	Gate-to-Source Voltage	± 10	V
E_{AS}	Single Pulse Avalanche Energy ②	100	mJ
I_{AR}	Avalanche Current ①	5.6	A
E_{AR}	Repetitive Avalanche Energy ①	4.3	mJ
dv/dt	Peak Diode Recovery dv/dt ③	5.5	V/ns
T_J	Operating Junction and Storage Temperature Range	-55 to +175	°C
T_{STG}			
	Mounting Torque, 6-32 or M3 screw	10 lbf•in (1.1 N•m)	

Thermal Resistance

	Parameter	Min.	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	—	—	3.5	°C/W
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	—	0.50	—	
$R_{\theta JA}$	Junction-to-Ambient	—	—	62	

Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	100	—	—	V	V _{GS} =0V, I _D = 250μA
ΔV _{(BR)DSS} /ΔT _J	Breakdown Voltage Temp. Coefficient	—	0.12	—	V/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance	—	—	0.54	Ω	V _{GS} =5.0V, I _D =3.4A ④
		—	—	0.76		V _{GS} =4.0V, I _D =2.8A ④
V _{GS(th)}	Gate Threshold Voltage	1.0	—	2.0	V	V _{DS} =V _{GS} , I _D = 250μA
g _{fs}	Forward Transconductance	1.9	—	—	S	V _{DS} =50V, I _D =3.4A ④
I _{DSS}	Drain-to-Source Leakage Current	—	—	25	μA	V _{DS} =100V, V _{GS} =0V
		—	—	250		V _{DS} =80V, V _{GS} =0V, T _J =150°C
I _{GSS}	Gate-to-Source Forward Leakage	—	—	100	nA	V _{GS} =10V
	Gate-to-Source Reverse Leakage	—	—	-100		V _{GS} =-10V
Q _g	Total Gate Charge	—	—	6.1	nC	I _D =5.6A
Q _{gs}	Gate-to-Source Charge	—	—	2.6		V _{DS} =80V
Q _{gd}	Gate-to-Drain ("Miller") Charge	—	—	3.3		V _{GS} =5.0V See Fig. 6 and 13 ④
t _{d(on)}	Turn-On Delay Time	—	9.3	—		V _{DD} =50V
t _r	Rise Time	—	47	—	ns	I _D =5.6A
t _{d(off)}	Turn-Off Delay Time	—	16	—		R _G =12Ω
t _f	Fall Time	—	18	—		R _D =8.4Ω See Figure 10 ④
L _D	Internal Drain Inductance	—	4.5	—		nH
L _S	Internal Source Inductance	—	7.5	—		
C _{iss}	Input Capacitance	—	250	—	pF	V _{GS} =0V
C _{oss}	Output Capacitance	—	80	—		V _{DS} =25V
C _{rss}	Reverse Transfer Capacitance	—	15	—		f=1.0MHz See Figure 5

Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
I _S	Continuous Source Current (Body Diode)	—	—	5.6	A	MOSFET symbol showing the integral reverse p-n junction diode.
I _{SM}	Pulsed Source Current (Body Diode) ①	—	—	18		
V _{SD}	Diode Forward Voltage	—	—	2.5	V	T _J =25°C, I _S =5.6A, V _{GS} =0V ④
t _{rr}	Reverse Recovery Time	—	110	130	ns	T _J =25°C, I _F =5.6A
Q _{rr}	Reverse Recovery Charge	—	0.50	0.65	μC	di/dt=100A/μs ④
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)				

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature (See Figure 11)
- ② V_{DD}=25V, starting T_J=25°C, L=4.8mH R_G=25Ω, I_{AS}=5.6A (See Figure 12)
- ③ I_{SD}≤5.6A, di/dt≤75A/μs, V_{DD}≤V_{(BR)DSS}, T_J≤175°C
- ④ Pulse width ≤ 300 μs; duty cycle ≤2%.

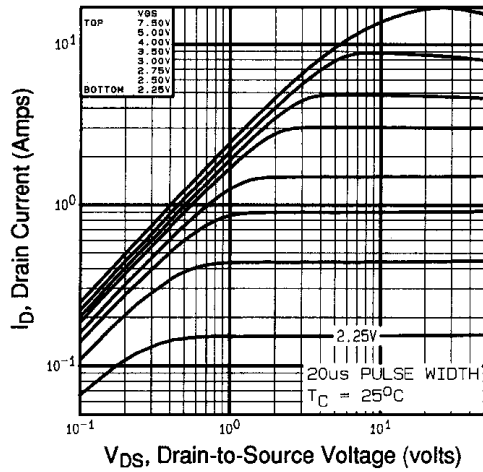


Fig 1. Typical Output Characteristics, $T_C=25^\circ\text{C}$

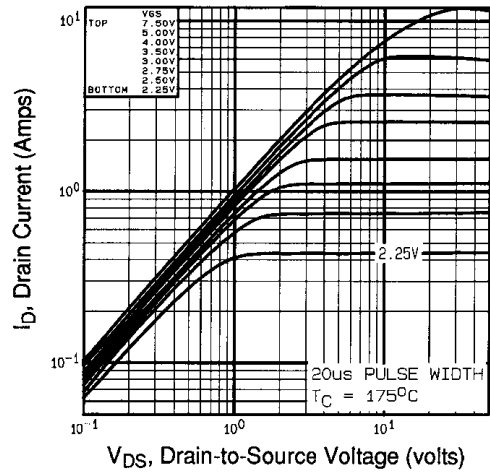


Fig 2. Typical Output Characteristics, $T_C=175^\circ\text{C}$

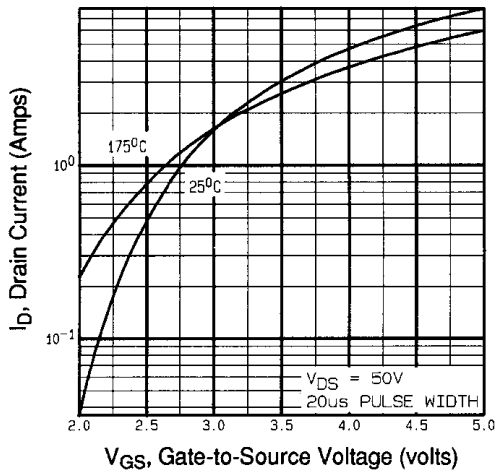


Fig 3. Typical Transfer Characteristics

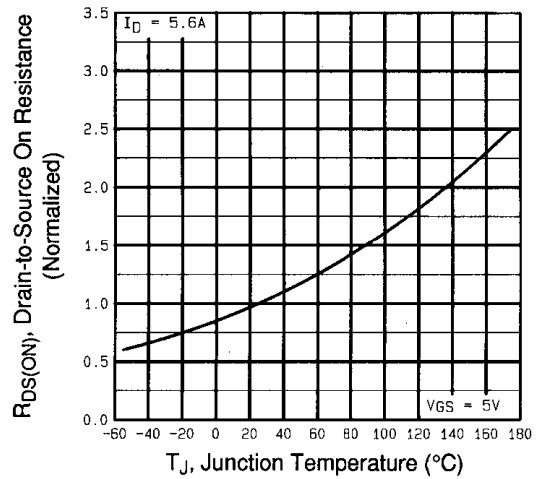


Fig 4. Normalized On-Resistance Vs. Temperature

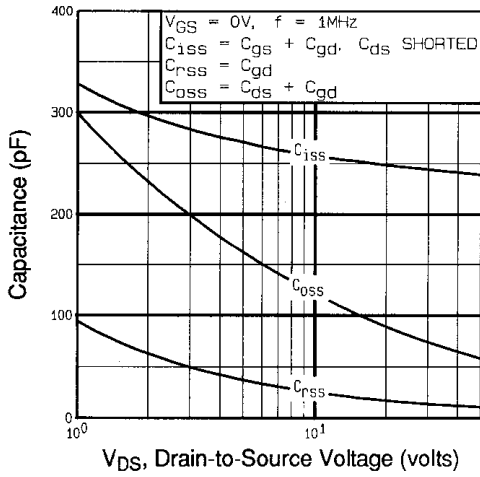


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

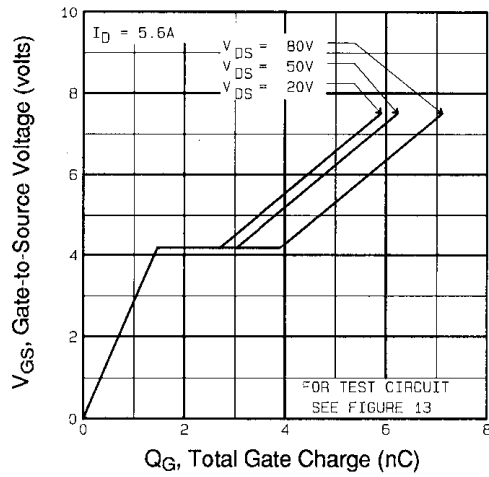


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

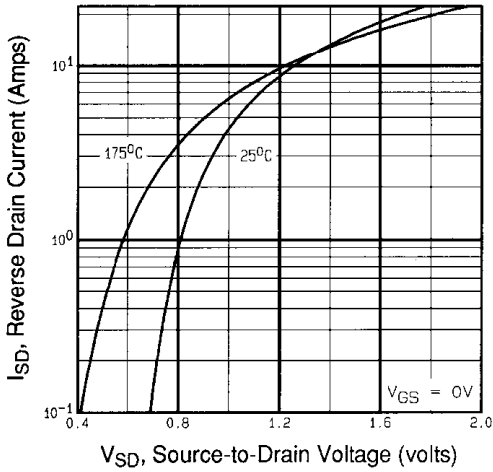


Fig 7. Typical Source-Drain Diode Forward Voltage

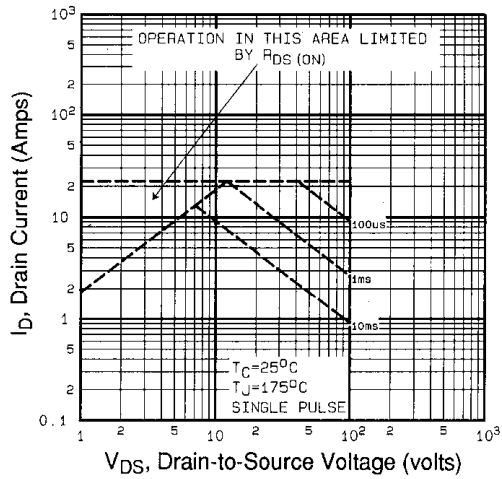


Fig 8. Maximum Safe Operating Area

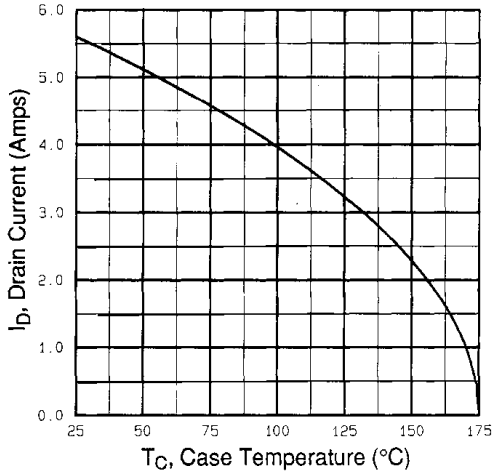


Fig 9. Maximum Drain Current Vs. Case Temperature

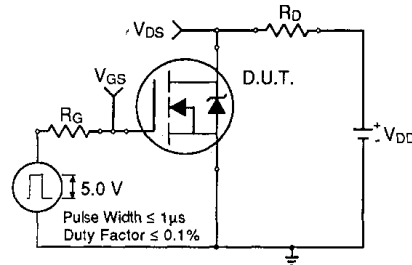


Fig 10a. Switching Time Test Circuit

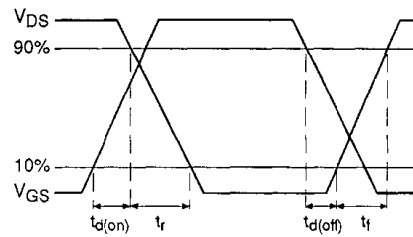


Fig 10b. Switching Time Waveforms

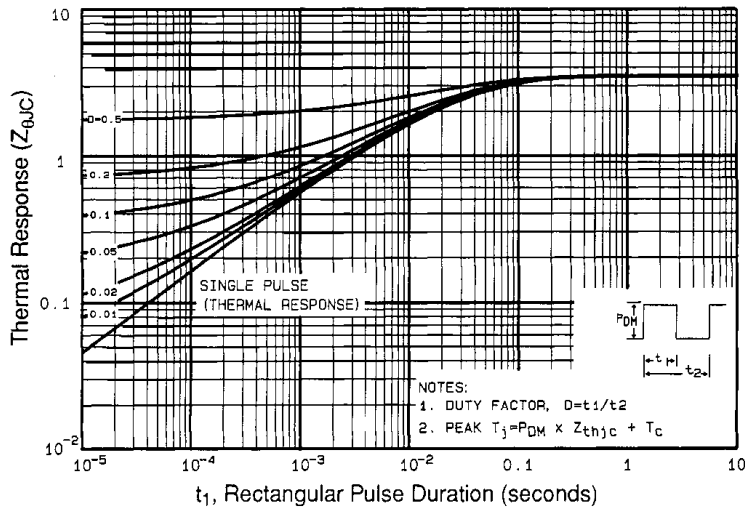


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

IRL510PbF

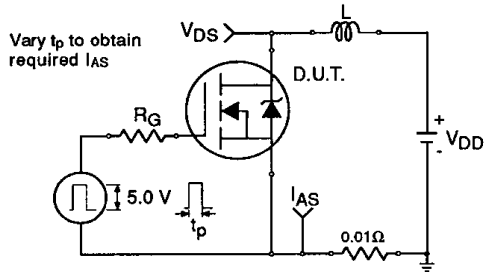


Fig 12a. Unclamped Inductive Test Circuit

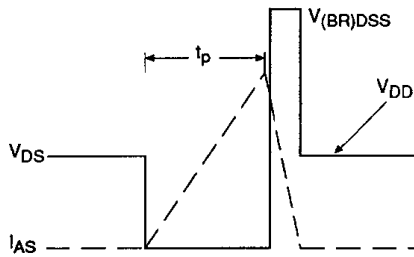


Fig 12b. Unclamped Inductive Waveforms

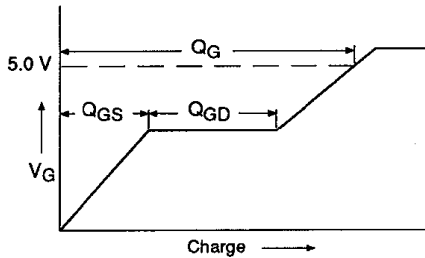


Fig 13a. Basic Gate Charge Waveform

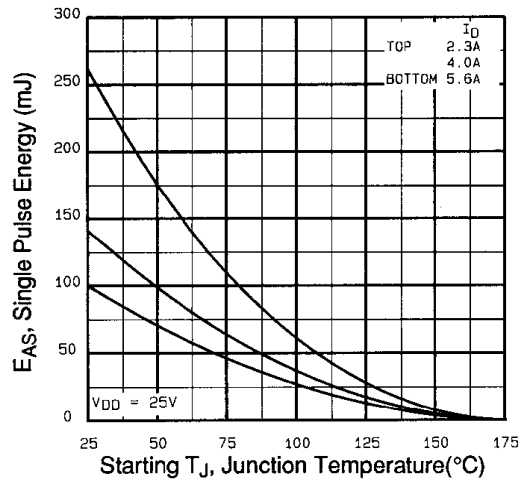


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

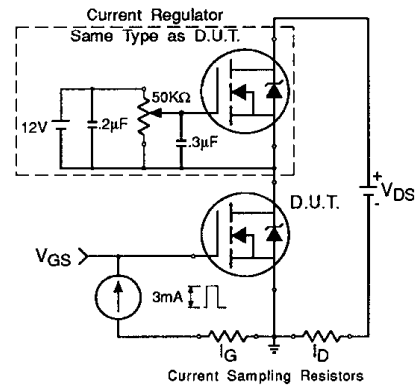
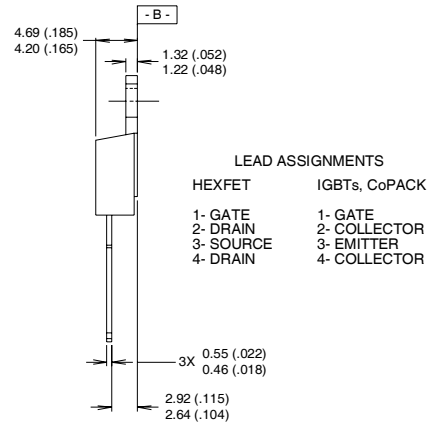
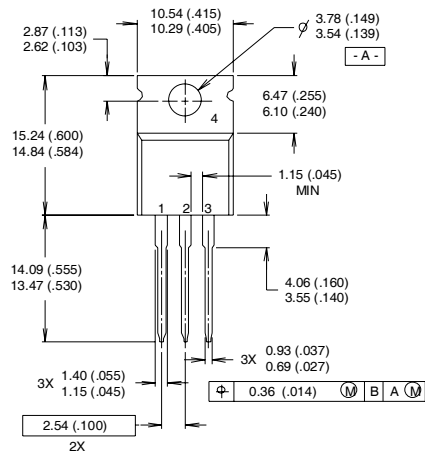


Fig 13b. Gate Charge Test Circuit

Appendix A: Figure 14, Peak Diode Recovery dv/dt Test Circuit – See page 1505

TO-220AB Package Outline

Dimensions are shown in millimeters (inches)



LEAD ASSIGNMENTS

HEXFET	IGBTs, CoPACK
1- GATE	1- GATE
2- DRAIN	2- COLLECTOR
3- SOURCE	3- EMITTER
4- DRAIN	4- COLLECTOR

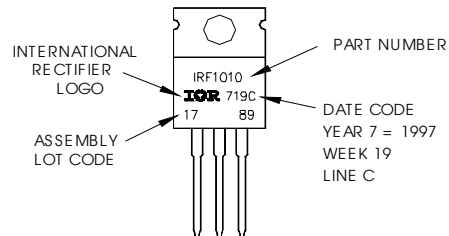
NOTES:

- 1 DIMENSIONING & TOLERANCING PER ANSI Y14.5M, 1982.
- 2 CONTROLLING DIMENSION : INCH

- 3 OUTLINE CONFORMS TO JEDEC OUTLINE TO-220AB.
- 4 HEATSINK & LEAD MEASUREMENTS DO NOT INCLUDE BURRS.

TO-220AB Part Marking Information

EXAMPLE: THIS IS AN IRF1010
 LOT CODE 1789
 ASSEMBLED ON WW 19, 1997
 IN THE ASSEMBLY LINE "C"
Note: "P" in assembly line
 position indicates "Lead-Free"



Data and specifications subject to change without notice.